

SEMITRANS[®] 10

IGBT R8 Modules

SKM1000GAR17R8

Features*

- Symmetrical current sharing
- Low-inductive module design
- High mechanical robustness
- UL recognized, file no. E63532

Typical Applications

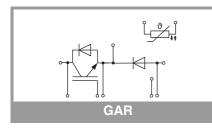
- Brake chopper
- Windturbines

Remarks

Recommended $T_{jop} = -40 \dots + 150^{\circ}C$

Symbol	Conditions		Values	Unit	
IGBT					
V _{CES}	T _i = 25 °C		1700		
I _C	T 175 00	T _c = 25 °C	1574	Α	
	Τ _j = 175 °C	T _c = 100 °C	1027	А	
I _{Cnom}			1000	А	
I _{CRM}			2000	А	
V _{GES}			-20 20	V	
t _{psc}	$V_{CC} = 1200 V$ $V_{GE} \le 15 V$ $V_{CES} \le 1700 V$	T _j = 150 °C	10	μs	
Tj			-40 175	°C	
Inverse d	iode				
V _{RRM}	T _j = 25 °C		1700	V	
I _F	– T _j = 175 °C	T _c = 25 °C	1449	Α	
		T _c = 100 °C	905	Α	
I _{FRM}			2000	А	
I _{FSM}	t _p = 10 ms, sin 180°, T _i = 25 °C		6240		
Tj			-40 175	°C	
Freewhee	ling diode				
V _{RRM}	T _i = 25 °C		1700	V	
I _F	T _j = 175 °C	T _c = 25 °C	1449	А	
		T _c = 100 °C	905	Α	
I _{FRM}			2000	А	
I _{FSM}	t _p = 10 ms, sin 180°, T _j = 25 °C		6240	А	
Tj			-40 175	°C	
Module	•				
T _{stg}			-40 150	°C	
Visol	AC sinus 50 Hz, t = 1 min		4000		

Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
IGBT						
V _{CE(sat)}	I _C = 1000 A	T _j = 25 °C		1.66	1.99	V
	V _{GE} = 15 V chiplevel	T _j = 150 °C		2.01	2.33	V
V _{CE0}	chiplevel	T _j = 25 °C		1.06	1.12	V
C		T _j = 150 °C		0.95	1.05	V
r _{CE}	V _{GE} = 15 V	T _j = 25 °C		0.60	0.87	mΩ
	chiplevel	T _j = 150 °C		1.06	1.28	mΩ
V _{GE(th)}	V _{CE} = 10 V, I _C = 36 mA		5	5.8	6.5	V
I _{CES}	$V_{GE} = 0 \text{ V}, V_{CE} = 1700 \text{ V}, T_j = 25 ^{\circ}\text{C}$				6.0	mA
C _{ies}	V _{CE} = 25 V V _{GE} = 0 V	f = 1 MHz		90.0		nF
C _{oes}		f = 1 MHz		3.00		nF
C _{res}		f = 1 MHz		0.24		nF
Q_{G}	V _{GE} = - 15 V+ 15 V			5640		nC
R _{Gint}	T _j = 25 °C			1.7		Ω





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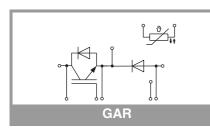
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Conditions $V_{CC} = 900 V$ $I_C = 1000 A$ $V_{GE} = +15/-15 V$ $R_{G on} = 0.7 \Omega$ $R_{G off} = 0.7 \Omega$	T _j = 150 °C T _j = 150 °C	min.	typ.	max.	Unit
$\begin{split} I_{C} &= 1000 \text{ A} \\ V_{GE} &= +15/\text{-}15 \text{ V} \\ R_{G \text{ on}} &= 0.7 \ \Omega \end{split}$	T _j = 150 °C				
$\begin{split} I_{C} &= 1000 \text{ A} \\ V_{GE} &= +15/\text{-}15 \text{ V} \\ R_{G \text{ on}} &= 0.7 \ \Omega \end{split}$	T _j = 150 °C	1			
$V_{GE} = +15/-15 V$ $R_{G \text{ on}} = 0.7 \Omega$	T _j = 150 °C		450		ns
$R_{G \text{ on}} = 0.7 \Omega$,		95		ns
	T _i = 150 °C		415		mJ
	T _i = 150 °C		620		ns
di/dt _{on} = 9.7 kA/µs	T _i = 150 °C		155		ns
$di/dt_{off} = 5.5 \text{ kA/}\mu\text{s}$					
dv/dt = 4300 V/μs L _s = 36 nH	T _j = 150 °C		345		mJ
per IGBT				0.03	K/W
per IGBT ($\lambda_{grease}=0$.81 W/(m*K))		0.016		K/W
ode		1			
I _F = 1000 A	T _i = 25 °C		1.78	2.12	V
$V_{GE} = 0 V$			1 81	2 14	V
cniplevel	-				
chiplevel					V
	,				V
chiplevel	,				mΩ
1 1000 4				0.92	mΩ
	-				A
	-		355		μC
V _R = 900 V	T _j = 150 °C		185		mJ
per diode	•			0.042	K/W
per diode ($\lambda_{grease}=0$.81 W/(m*K))		0.017		K/W
ing diode					
I _F = 1000 A	T _j = 25 °C		1.78	2.12	V
$V_{GE} = 0 V$	T _i = 150 °C		1.81	2.14	V
chiplevel	T; = 25 °C		1.32	1.56	V
					V
	•				mΩ
chiplevel	•				mΩ
l⊧ = 1000 A	,			0.02	A
di/dt _{off} = 9.2 kA/µs	,				μC
	-				mJ
	1, = 150 0		105	0.040	
	04 14// +1/)		0.047	0.042	K/W
per diode (Agrease=0	.81 W/(m^K))		0.017		K/W
		1	10		рЦ
monourod					nH
calculated without thermal coupling			0.2		mΩ K/W
(A _{grease} =0.81 W/(m K)) including thermal coupling, T _s underneath module (A _{grease} =0.81 W/(m*K))			0.007		K/W
to heat sink M5		4		6	Nm
	to terminals M8	8		10	Nm
	to terminals M4	1.8		2.1	Nm
	I	1		1250	g
	$\begin{split} & L_{s} = 36 \text{ nH} \\ & per IGBT \\ & per IGBT (\lambda_{grease} = 0) \\ & ode \\ & I_{F} = 1000 \text{ A} \\ & V_{GE} = 0 \text{ V} \\ & chiplevel \\ & chiplevel \\ & chiplevel \\ & chiplevel \\ & I_{F} = 1000 \text{ A} \\ & V_{GE} = -15 \text{ V} \\ & di/dt_{off} = 9.2 \text{ kA/\mu s} \\ & V_{R} = 900 \text{ V} \\ & per diode \\ & per diode \\ & per diode \\ & I_{F} = 1000 \text{ A} \\ & V_{GE} = 0 \text{ V} \\ & level = chiplevel \\ & l_{F} = 1000 \text{ A} \\ & di/dt_{off} = 9.2 \text{ kA/\mu s} \\ & V_{GE} = 0 \text{ V} \\ & level = chiplevel \\ & chiplevel \\ & chiplevel \\ & per diode \\ & measured per swite \\ & calculated without t \text{ t} \\ & (\lambda_{grease} = 0.81 \text{ W/(m^*)} \\ & including thermal chipped \\ & (\lambda_{grease} = 0.81 \text{ W/(m^*)} \\ & (M^*) \\ & (M^*$	$\begin{split} & \text{L}_{\text{s}} = 36 \text{ nH} \\ & \text{per IGBT} \\ & \text{per IGBT } (\lambda_{\text{grease}} = 0.81 \text{ W/(m^*\text{K})}) \\ \hline \text{ode} \\ & \text{I}_{\text{F}} = 1000 \text{ A} \\ & \text{V}_{\text{GE}} = 0 \text{ V} \\ & \text{chiplevel} \\ \hline \text{T}_{\text{j}} = 150 \ ^{\circ}\text{C} \\ & \text{T}_{\text{j}} = 150 \ ^{\circ}\text{C} \\ & \text{T}_{\text{j}} = 150 \ ^{\circ}\text{C} \\ & \text{T}_{\text{j}} = 150 \ ^{\circ}\text{C} \\ \hline \text{T}_{\text{j}} = 150 \ ^{\circ}\text{C} \\ & \text{per diode} \\ & \text{per diode} \\ & \text{per diode} \\ & \text{per diode} \\ & \text{I}_{\text{F}} = 1000 \text{ A} \\ & \text{V}_{\text{GE}} = 0 \text{ V} \\ & \text{level} = \text{chiplevel} \\ \hline & \text{T}_{\text{j}} = 25 \ ^{\circ}\text{C} \\ & \text{T}_{\text{j}} = 150 \ ^{\circ}\text{C} \\ & \text{T}_{\text{j}} = 150 \ ^{\circ}\text{C} \\ & \text{T}_{\text{j}} = 150 \ ^{\circ}\text{C} \\ \\ & \text{chiplevel} \\ \hline & \text{I}_{\text{F}} = 1000 \text{ A} \\ & \text{di/dt}_{\text{off}} = 9.2 \text{ kA/\mus} \\ & \text{V}_{\text{GE}} = 0 \text{ V} \\ & \text{level} = \text{chiplevel} \\ \hline & \text{T}_{\text{j}} = 25 \ ^{\circ}\text{C} \\ & \text{T}_{\text{j}} = 150 \ ^{\circ}\text{C} \\ & \text{T}_{\text{j}} = 150 \ ^{\circ}\text{C} \\ \\ & \text{T}_{\text{j}} = 150 \ ^{\circ}\text{C} \\ & \text{per diode} \\ & \text{per diode} \\ & \text{per diode} \\ & \text{per diode} (\lambda_{\text{grease}} = 0.81 \ \text{W/(m^*\text{K})) \\ & \text{including thermal coupling} \\ & (\lambda_{\text{grease}} = 0.81 \ \text{W/(m^*\text{K})) \\ & \text{including thermal coupling}, \\ & \text{T}_{\text{s} \text{ underneath module} \\ & (\lambda_{\text{grease}} = 0.81 \ \text{W/(m^*\text{K})) \\ & \text{to heat sink M5} \\ \hline \end{array}$	$\begin{array}{c c c c c c c c c c c c c c c c c c c $	$\begin{split} & \begin{array}{c} L_{s} = 36 \text{ nH} & \begin{array}{c} J & \text{NM} & \text{NM} & \text{NM} \\ \hline \text{per IGBT} & & \begin{array}{c} 0.016 \\ \hline \text{NGe} & & \end{array} \\ \hline \text{I}_{F} = 1000 \text{ A} & \begin{array}{c} T_{j} = 25 \ ^{\circ}\text{C} & & 1.78 \\ \hline T_{j} = 150 \ ^{\circ}\text{C} & & 1.32 \\ \hline T_{j} = 150 \ ^{\circ}\text{C} & & 1.08 \\ \hline T_{j} = 25 \ ^{\circ}\text{C} & & 0.46 \\ \hline T_{j} = 150 \ ^{\circ}\text{C} & & 0.73 \\ \hline \text{I}_{F} = 1000 \text{ A} & \\ \hline \text{V}_{GE} = -15 \text{ V} & \\ \text{di/dt}_{off} = 9.2 \text{ kA/\mus} & \\ \hline \text{V}_{R} = 900 \text{ V} & \hline \text{T}_{j} = 150 \ ^{\circ}\text{C} & & 1.85 \\ \hline \text{per diode} & & \\ \hline \text{I}_{F} = 1000 \text{ A} & \\ \hline \text{V}_{GE} = 0 \text{ V} & \\ \hline \text{I}_{F} = 1000 \text{ A} & \\ \hline \text{I}_{F} = 1000 \text{ A} & \\ \hline \text{I}_{F} = 1000 \text{ A} & \\ \hline \text{T}_{j} = 25 \ ^{\circ}\text{C} & & 1.78 \\ \hline \text{T}_{j} = 150 \ ^{\circ}\text{C} & & 1.81 \\ \hline \text{tevel} = \text{chiplevel} & \\ \hline \hline \text{T}_{j} = 25 \ ^{\circ}\text{C} & & 1.32 \\ \hline \text{T}_{j} = 150 \ ^{\circ}\text{C} & & 1.32 \\ \hline \text{T}_{j} = 150 \ ^{\circ}\text{C} & & 1.32 \\ \hline \text{Chiplevel} & \\ \hline \hline \text{T}_{j} = 25 \ ^{\circ}\text{C} & & 1.32 \\ \hline \text{T}_{j} = 150 \ ^{\circ}\text{C} & & 1.32 \\ \hline \text{T}_{j} = 150 \ ^{\circ}\text{C} & & 1.32 \\ \hline \text{T}_{j} = 150 \ ^{\circ}\text{C} & & 0.73 \\ \hline \text{I}_{F} = 1000 \text{ A} & \\ \hline \text{T}_{j} = 150 \ ^{\circ}\text{C} & & 1.32 \\ \hline \text{T}_{j} = 150 \ ^{\circ}\text{C} & & 0.73 \\ \hline \text{I}_{F} = 1000 \text{ A} & \\ \hline \text{T}_{j} = 150 \ ^{\circ}\text{C} & & 0.73 \\ \hline \text{I}_{F} = 1000 \text{ A} & \\ \hline \text{T}_{j} = 150 \ ^{\circ}\text{C} & & 0.73 \\ \hline \text{I}_{F} = 1000 \text{ A} & \\ \hline \text{T}_{j} = 150 \ ^{\circ}\text{C} & & 1.85 \\ \hline \text{per diode} & \\ \hline \text{per diode} & & \\ \hline \text{I}_{T} = 150 \ ^{\circ}\text{C} & & 185 \\ \hline \text{per diode} & & \\ \hline \text{heasured per switch}, \ \text{T}_{C} = 25 \ ^{\circ}\text{C} & & 0.2 \\ \hline \text{calculated without thermal coupling} \\ \hline \text{(A}_{greass} = 0.81 \ \text{W/(m^{*}\text{K})) & \\ \hline \text{including thermal coupling}, \\ \hline \text{to terminals M8} & \\ \hline \end{array} \right$	$ \begin{array}{c c c c c c c c c c c c c c c c c c c $



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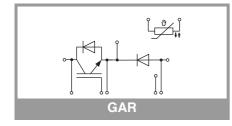
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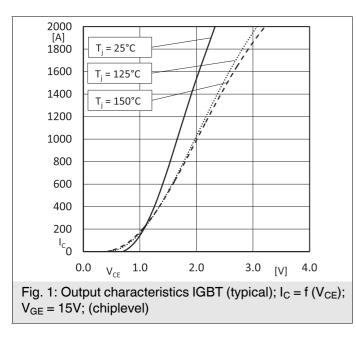
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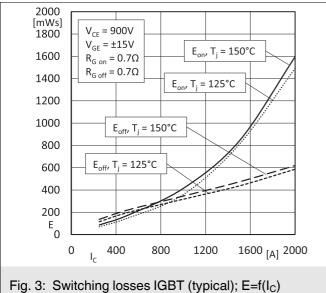
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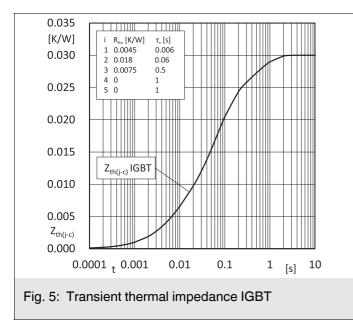
Characteristics

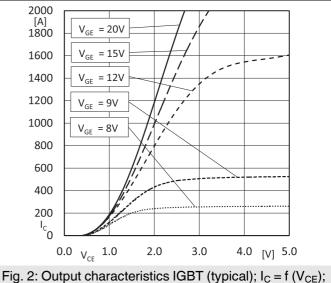
Symbol	Conditions	min.	typ.	max.	Unit	
Temperature Sensor						
R ₁₀₀	T _c =100°C (R ₂₅ =5 kΩ)		493 ± 5%		Ω	
B _{100/125}	R _(T) =R ₁₀₀ exp[B _{100/125} (1/T-1/T ₁₀₀)]; T[K];		3550 ±2%		К	

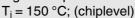












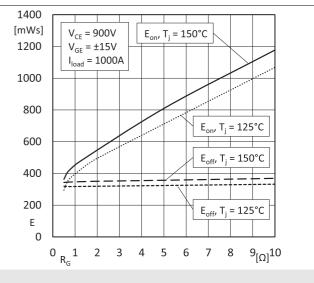
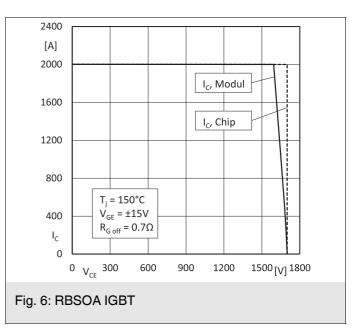
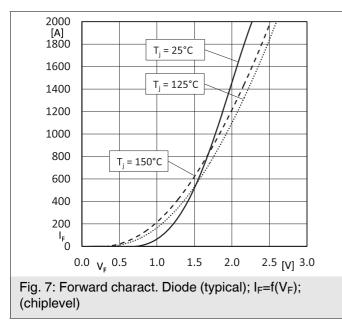
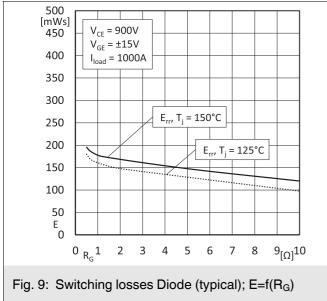
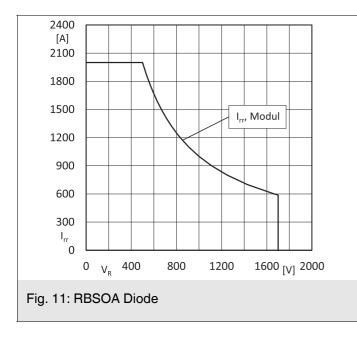


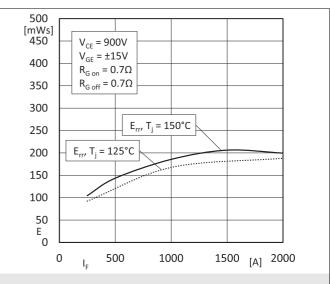
Fig. 4: Switching losses IGBT (typical); E=f(R_G)

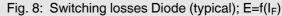


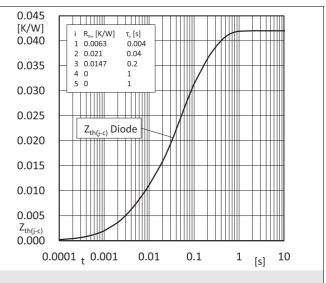


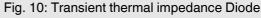


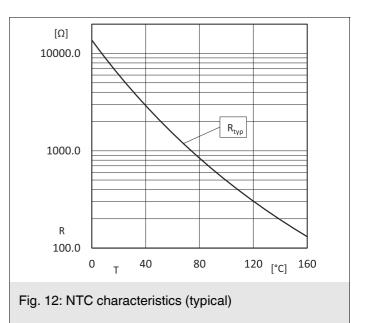


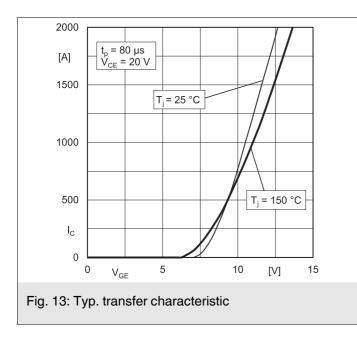


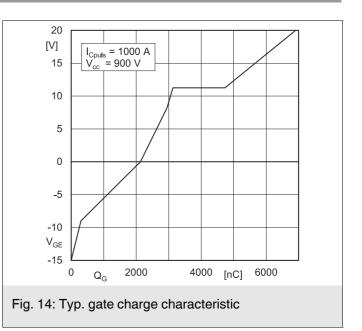


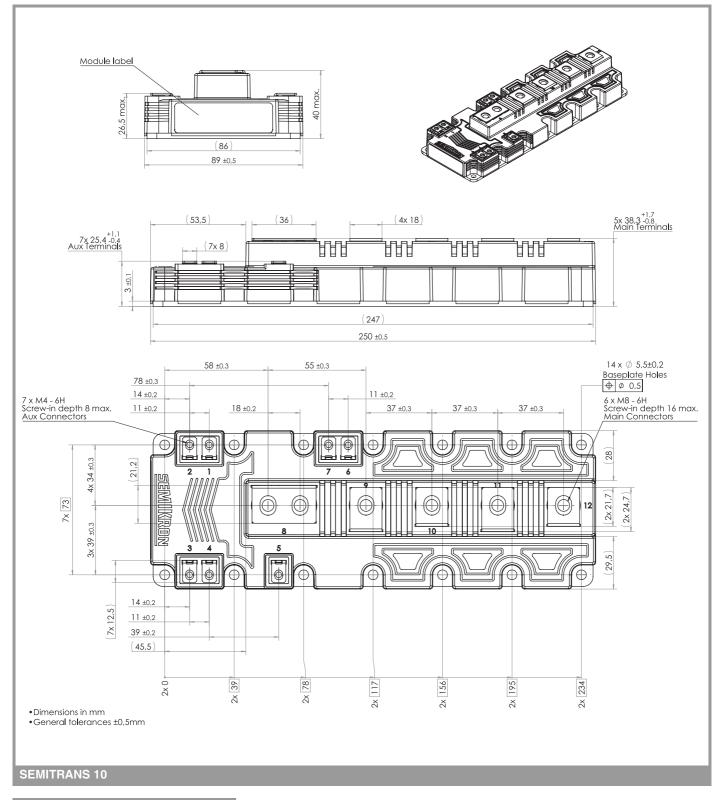


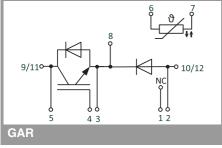












This is an electrostatic discharge sensitive device (ESDS) due to international standard IEC 61340.

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